



[10191 1517]

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s) : Pawel DRABAREK
Serial No. : 09/622,802
Filed : October 11, 2000
For : INTERFEROMETRIC MEASURING DEVICE FOR
DETECTING THE SHAPE OR DISTANCE IN
PARTICULAR OF ROUGH SURFACES

Examiner : M. LYONS

Art Unit : 2877

Assistant Commissioner
for Patents
Washington, D.C. 20231

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Date

Att'y's Reg. # 33,865

Att'y's Signature

AARON C. DEDITION

AMENDMENT

SIR:

In response to the Office Action mailed on August 28, 2002, please reconsider
the above-identified application based on the following:

IN THE CLAIMS:

11. (Amended) An interferometric measuring device for detecting one of a shape and a
distance of a rough surface, the measuring device comprising:

at least one spatially coherent beam gun unit for emitting a short time coherent
broad-band beam;

a first beam splitter for splitting the short time coherent broad band beam into
a first partial beam and a second partial beam;

a first device for one of modulating a phase of the first partial beam with
respect to a phase of the second partial beam, and for shifting a frequency of the first partial
beam with respect to a frequency of the second partial beam by a heterodyne frequency;

a time delay element arranged in a beam path of one of the first partial beam
and the second partial beam, for producing a difference of optical wavelengths of the first and
second partial beams, the difference being greater than a coherence length of the beam
emitted by the at least one spatially coherent beam gun unit;

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DEC - 4 - 2002
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